BUK753R4-30B



N-channel TrenchMOS standard level FET Rev. 2 — 21 April 2011

Product data sheet

Product profile 1.

1.1 General description

Standard level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product has been designed and qualified to the appropriate AEC standard for use in automotive critical applications.

1.2 Features and benefits

- AEC Q101 compliant
- Suitable for standard level gate drive sources
- Suitable for thermally demanding environments due to 175 °C rating

1.3 Applications

- 12 V loads
- Automotive systems

- General purpose power switching
- Motors, lamps and solenoids

1.4 Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{DS}	drain-source voltage	$T_j \ge 25 \text{ °C}; T_j \le 175 \text{ °C}$	-	-	30	V
I _D	drain current	$V_{GS} = 10 \text{ V; } T_{mb} = 25 \text{ °C;}$ see Figure 1; see Figure 3	[1] -	-	75	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	-	255	W
Static char	acteristics					
R _{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A};$ $T_j = 25 \text{ °C};$ see Figure 12; see Figure 13	-	2.9	3.4	mΩ



Table 1. Quick reference data ...continued

Parameter	Conditions	Min	Тур	Max	Unit
ruggedness					
non-repetitive drain-source avalanche energy	I_D = 75 A; $V_{sup} \le 30$ V; R_{GS} = 50 Ω ; V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; unclamped	-	-	1.3	J
haracteristics					
gate-drain charge	$I_D = 25 \text{ A}; V_{DS} = 24 \text{ V};$ $V_{GS} = 10 \text{ V};$ see <u>Figure 14</u>	-	23	-	nC
	non-repetitive drain-source avalanche energy	pruggedness non-repetitive drain-source avalanche energy $I_D = 75 \text{ A}; V_{sup} \le 30 \text{ V};$ $R_{GS} = 50 \Omega; V_{GS} = 10 \text{ V};$ $T_{j(init)} = 25 \text{ °C};$ $unclamped$ characteristics gate-drain charge $I_D = 25 \text{ A}; V_{DS} = 24 \text{ V};$ $V_{GS} = 10 \text{ V};$	ruggedness non-repetitive drain-source avalanche energy $I_D = 75 \text{ A; } V_{sup} \le 30 \text{ V;}$ - $R_{GS} = 50 \Omega; V_{GS} = 10 \text{ V;}$ $T_{j(init)} = 25 \text{ °C;}$ unclamped characteristics gate-drain charge $I_D = 25 \text{ A; } V_{DS} = 24 \text{ V;}$ - $V_{GS} = 10 \text{ V;}$	Pruggedness non-repetitive drain-source avalanche energy $I_D = 75 \text{ A}; V_{sup} \le 30 \text{ V};$	Pruggedness non-repetitive drain-source avalanche energy

^[1] Continuous current is limited by package.

2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate		
2	D	drain	mb	D
3	S	source		G (FA)
mb	D	mounting base; connected to drain		mbb076 S
			SOT78A (TO-220AB)	

3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
BUK753R4-30B	TO-220AB	plastic single-ended package; heatsink mounted; 1 mounting hole; 3-lead TO-220AB	SOT78A

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C	-	30	V
V_{DGR}	drain-gate voltage	$R_{GS} = 20 \text{ k}\Omega$	-	30	V
V_{GS}	gate-source voltage		-20	20	V
I _D	drain current	T_{mb} = 25 °C; V_{GS} = 10 V; see <u>Figure 1</u> ;	[1][2]	198	Α
		see Figure 3	[3]	75	Α
		T_{mb} = 100 °C; V_{GS} = 10 V; see <u>Figure 1</u>	[3]	75	Α
I _{DM}	peak drain current	T_{mb} = 25 °C; pulsed; $t_p \le 10 \mu s$; see Figure 3	-	794	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	255	W
T _{stg}	storage temperature		-55	175	°C
Tj	junction temperature		-55	175	°C
Source-drai	n diode				
Is	source current	T _{mb} = 25 °C	[1][2]	198	Α
			[3] _	75	Α
I _{SM}	peak source current	pulsed; $t_p \le 10 \ \mu s$; $T_{mb} = 25 \ ^{\circ}C$	-	794	Α
Avalanche r	uggedness				
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	I_D = 75 A; $V_{sup} \le 30$ V; R_{GS} = 50 Ω; V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; unclamped	-	1.3	J
E _{DS(AL)R}	repetitive drain-source avalanche energy		[4][5]	-	J

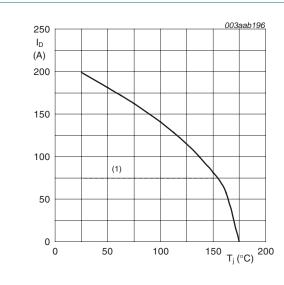
^[1] Current is limited by power dissipation chip rating.

^[2] Refer to document 9397 750 12572 for further information.

^[3] Continuous current is limited by package.

^[4] Max value not quoted; Single-shot avalanche rating limited by T_i(max) of 175 °C.

^[5] Repetitive avalanche rating limited by an average T_j of 170 °C; Refer to application note AN10273 for further information.



 $V_{\it GS} \geq 5 \; V \label{eq:VGS}$ (1) Capped at 75 A due to package.

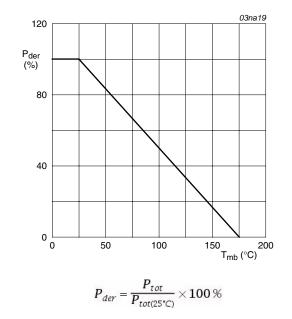
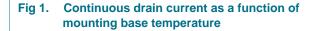
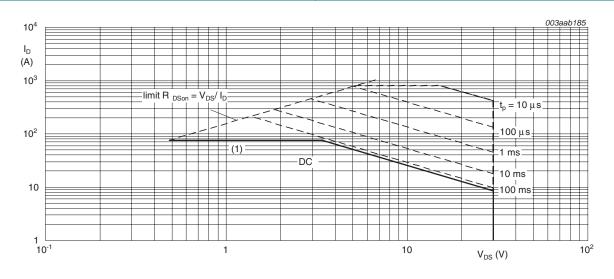


Fig 2. Normalized total power dissipation as a function of mounting base temperature





 T_{mb} = 25 °C; I_{DM} is single pulse (1) Capped at 75 A due to package.

Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base		-	-	0.59	K/W
R _{th(j-a)}	thermal resistance from junction to ambient	vertical in free air	-	60	-	K/W

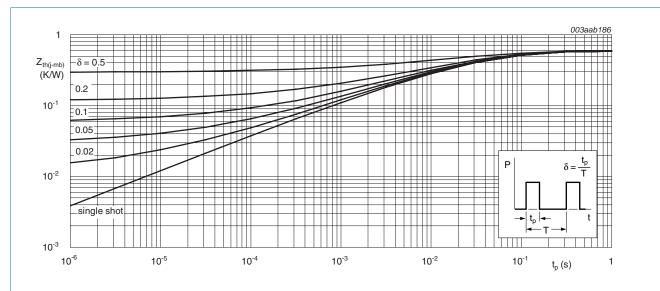


Fig 4. Transient thermal impedance from junction to mounting base as a function of pulse duration

6. Characteristics

Table 6. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	aracteristics					
$V_{(BR)DSS}$	drain-source	$I_D = 250 \ \mu A; \ V_{GS} = 0 \ V; \ T_j = -55 \ ^{\circ}C$	27	-	-	V
	breakdown voltage	$I_D = 250 \ \mu A; \ V_{GS} = 0 \ V; \ T_j = 25 \ ^{\circ}C$	30	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1 \text{ mA}$; $V_{DS} = V_{GS}$; $T_j = 25 \text{ °C}$; see <u>Figure 10</u> ; see <u>Figure 11</u>	2	3	4	V
V_{GSth}	gate-source threshold voltage	$I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = -55$ °C; see <u>Figure 10</u> ; see <u>Figure 11</u>	-	-	4.4	V
		$I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = 175$ °C; see <u>Figure 10</u> ; see <u>Figure 11</u>	1	-	-	V
I _{DSS}	drain leakage current	$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	0.05	10	μΑ
I _{GSS}	gate leakage current	$V_{GS} = 20 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	2	100	nA
		$V_{GS} = -20 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	2	100	nA
R _{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}$; $I_D = 25 \text{ A}$; $T_j = 25 \text{ °C}$; see Figure 12; see Figure 13	-	2.9	3.4	mΩ
		V_{GS} = 10 V; I_D = 25 A; T_j = 175 °C; see <u>Figure 12</u> ; see <u>Figure 13</u>	-	-	6.5	mΩ
I _{DSS}	drain leakage current	$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 175 \text{ °C}$	-	-	500	μΑ
Dynamic	characteristics					
Q _{G(tot)}	total gate charge	$I_D = 25 \text{ A}; V_{DS} = 24 \text{ V}; V_{GS} = 10 \text{ V};$	-	75	-	nC
Q_{GS}	gate-source charge	see Figure 14	-	19	-	nC
Q_{GD}	gate-drain charge		-	23	-	nC
C _{iss}	input capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz};$	-	3713	4951	pF
C _{oss}	output capacitance	T _j = 25 °C; see <u>Figure 15</u>	-	1249	1499	pF
C _{rss}	reverse transfer capacitance		-	460	630	pF
t _{d(on)}	turn-on delay time	$V_{DS} = 30 \text{ V}; R_L = 1.2 \Omega; V_{GS} = 10 \text{ V};$	-	32	-	ns
t _r	rise time	$R_{G(ext)} = 10 \Omega$	-	64	-	ns
$t_{d(off)}$	turn-off delay time		-	89	-	ns
t _f	fall time		-	71	-	ns
L _D	internal drain inductance	from contact screw on mounting base to centre of die	-	3.5	-	nΗ
		from drain lead 6 mm from package to centre of die	-	4.5	-	nΗ
L _S	internal source inductance	from source lead to source bond pad	-	7.5	-	nΗ
Source-d	rain diode					
V_{SD}	source-drain voltage	$I_S = 25 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C};$ see Figure 16	-	0.85	1.2	V
t _{rr}	reverse recovery time	$I_S = 20 \text{ A; } dI_S/dt = -100 \text{ A/}\mu\text{s; } V_{GS} = 0 \text{ V;}$	-	70	-	ns
	recovered charge	$V_{DS} = 30 \text{ V}$		58		nC

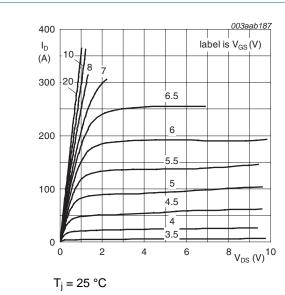


Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical values

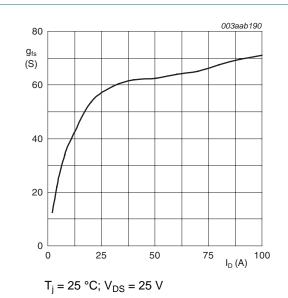


Fig 7. Forward transconductance as a function of drain current; typical values

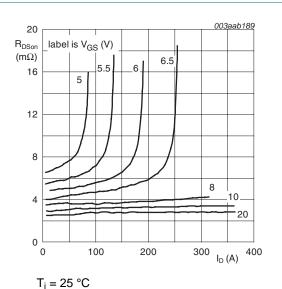


Fig 6. Drain-source on-state resistance as a function of drain current; typical values

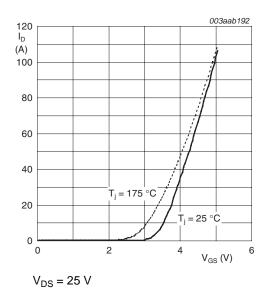


Fig 8. Transfer characteristics: drain current as a function of gate-source voltage; typical values

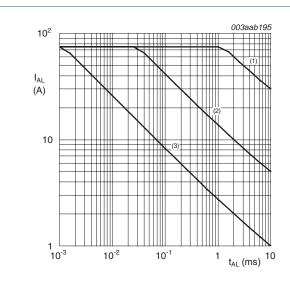
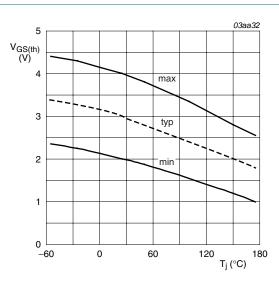
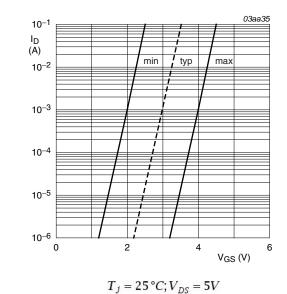


Fig 9. Single shot and repetitive avalanche rating; avalanche current as a function of avalanche time



$$I_D = 1mA; V_{DS} = V_{GS}$$

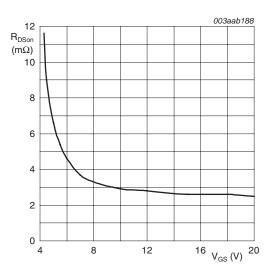
Fig 10. Gate-source threshold voltage as a function of junction temperature



 $T_j = 25 \text{ C}, V_{DS} = 5V$

gate-source voltage

Fig 11. Sub-threshold drain current as a function of



 $T_j = 25 \,{}^{\circ}C; I_D = 10 \, A$

Fig 12. Drain-source on-state resistance as a function of gate-source voltage; typical values

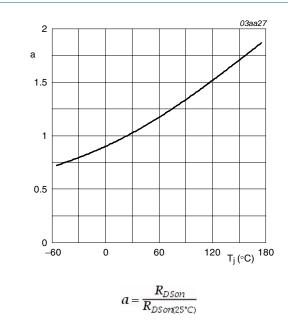


Fig 13. Normalized drain-source on-state resistance factor as a function of junction temperature

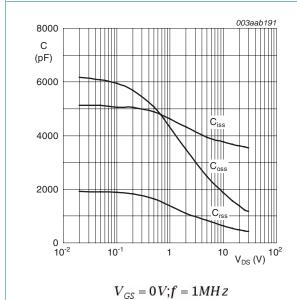


Fig 15. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values.

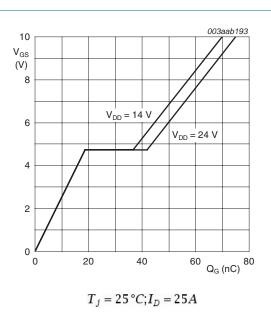


Fig 14. Gate-source voltage as a function of gate charge; typical values

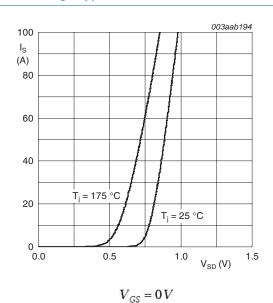
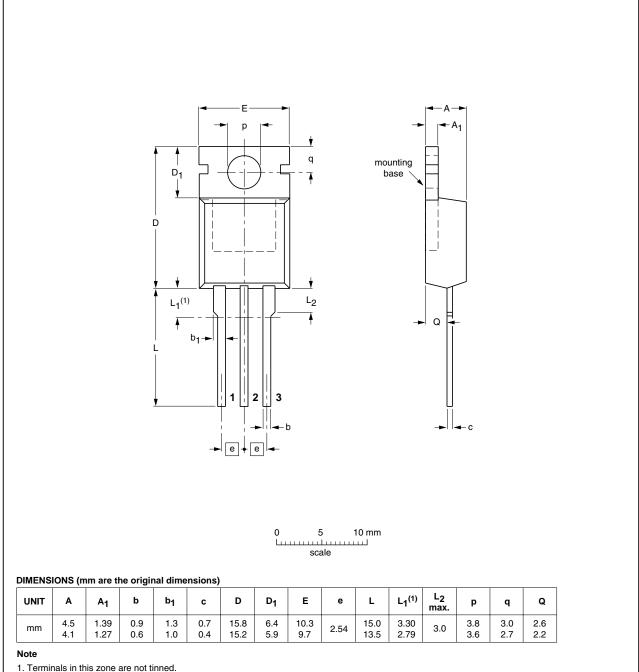


Fig 16. Source (diode forward) current as a function of source-drain (diode forward) voltage; typical values

Package outline

Plastic single-ended package; heatsink mounted; 1 mounting hole; 3-lead TO-220AB

SOT78A



OUTLINE		REFER	ENCES	EUROPEAN	ISSUE DATE
VERSION	IEC	JEDEC	JEITA	PROJECTION	ISSUE DATE
SOT78A		3-lead TO-220AB	SC-46		03-01-22 05-03-14

Fig 17. Package outline SOT78A (TO-220AB)

BUK753R4-30B

8. Revision history

Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
BUK753R4-30B v.2	20110421	Product data sheet	-	BUK75_763R4-30B_1
Modifications:	 The format of this of NXP Semicondu 	data sheet has been rede uctors.	signed to comply with the	e new identity guidelines
	 Legal texts have be 	een adapted to the new c	ompany name where app	oropriate.
	 Type number BUK 	753R4-30B separated fro	m data sheet BUK75_76	3R4-30B_1.
BUK75_763R4-30B_1	20060105	Product specification	-	-

9. Legal information

9.1 Data sheet status

Document status [1] [2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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Contact Us:

Address:

401 Building No.5, JiuGe Business Center, Lane 2301, Yishan Rd Minhang District, Shanghai , China

> Sales:

Direct +86 (21) 6401-6692

Email amall@ameya360.com

QQ 800077892

Skype ameyasales1 ameyasales2

Customer Service :

Email service@ameya360.com

Partnership :

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